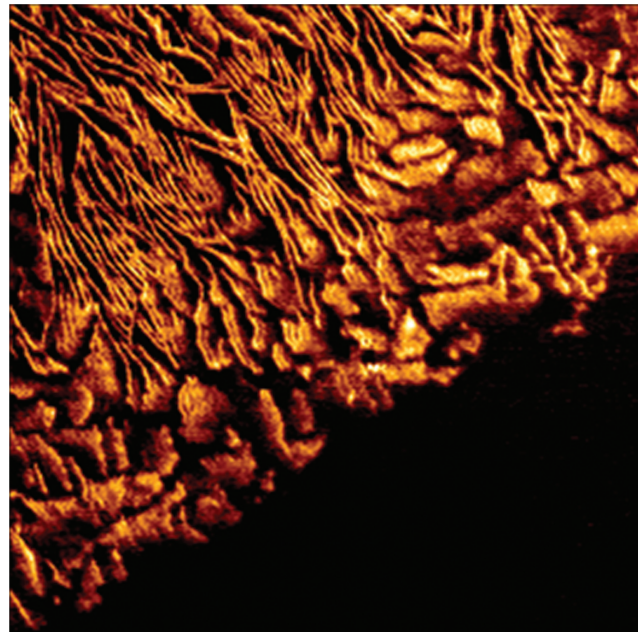
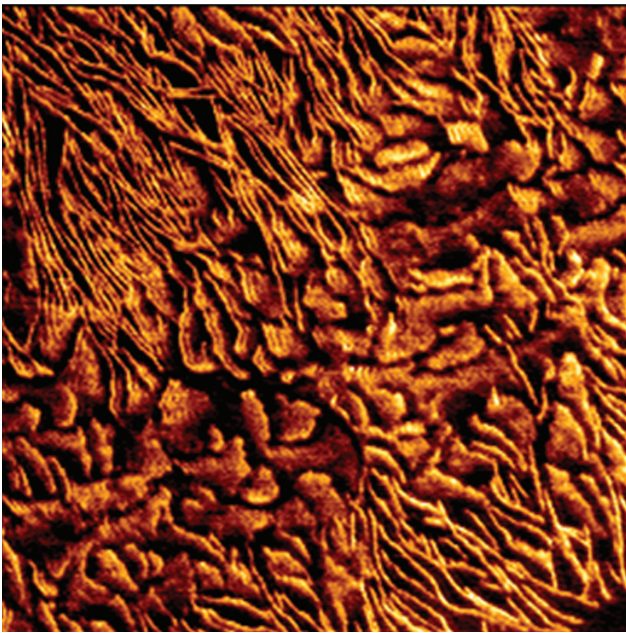
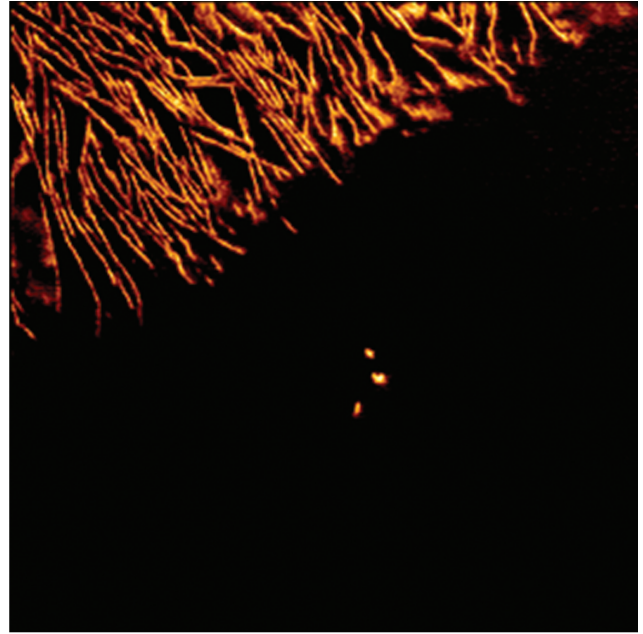
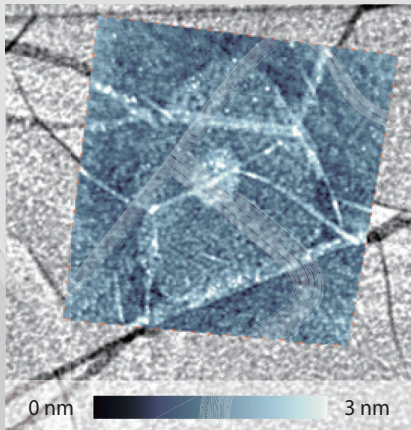


# Microscopy TODAY

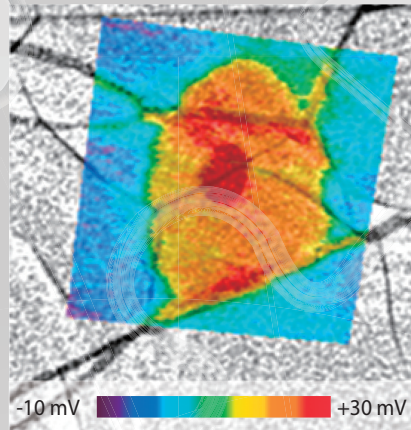
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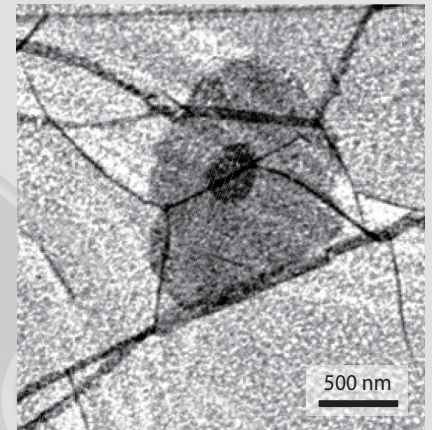
## AFM/SEM Comparative Measurements of Graphene



AFM/SEM Overlay\*



KFM/SEM Overlay\*



SEM

\*Overlay images created by using AZblend (ASTRON, Inc.).

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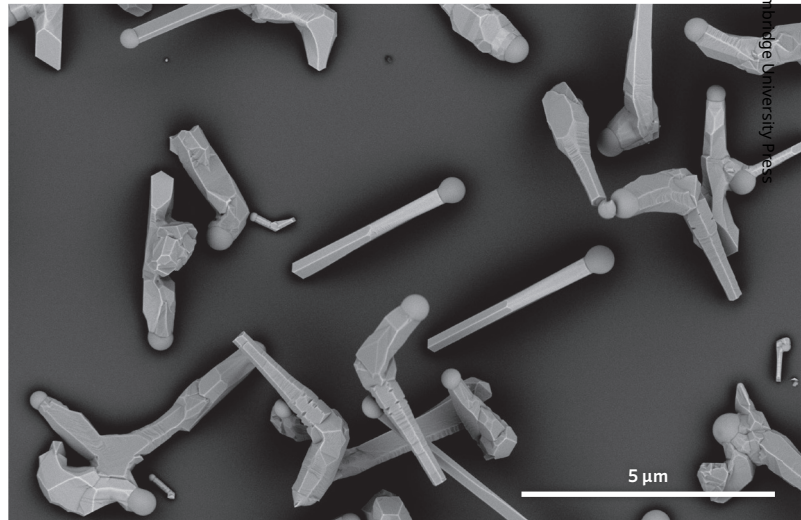
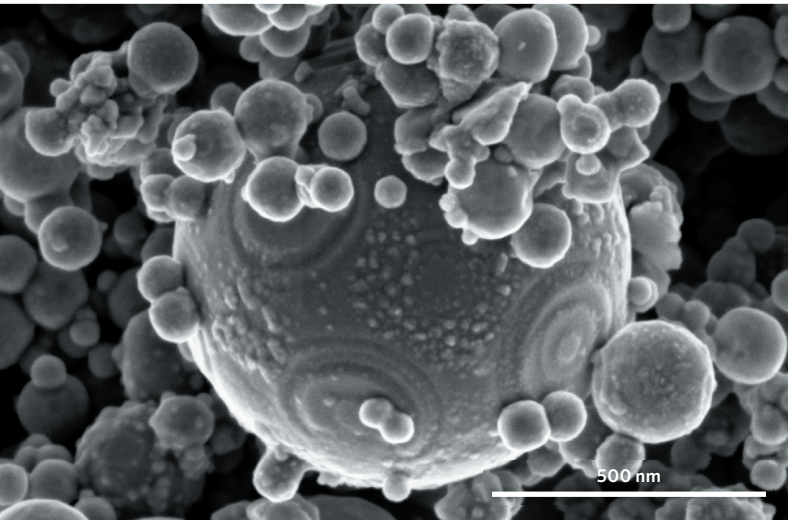
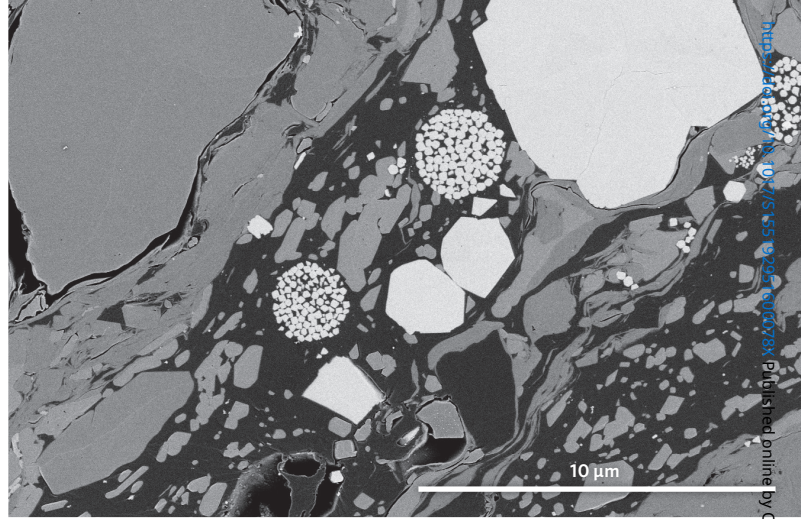
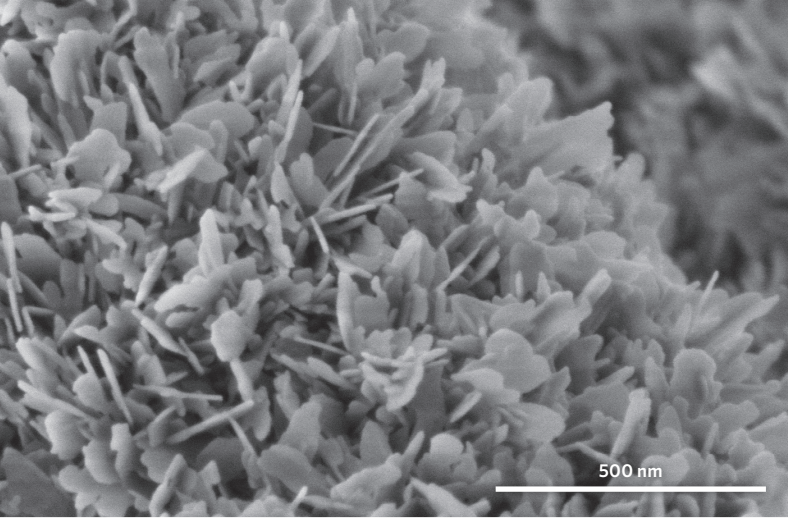
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Top left, *Hydroxyapatite crystals*. Sample courtesy of Devin Wu, FEI China and Shanghai Institute of Ceramics. Top right, *Shale*. Bottom left, *Fe/Sn nanoparticles*. Bottom right, *Self-catalyzed GaAs wires*. Sample courtesy David Fuster, Andrés Raya, Álvaro San Paulo and Maria Ujue González, IMM Madrid (CNM-CSIC).

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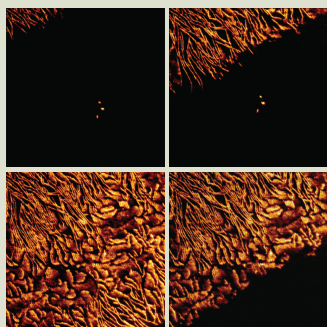
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### About the Cover



Intermittent contact mode AFM phase images of a thermoplastic polymer as it crystallizes. Clockwise from upper left:  $t = 0$  sec,  $t = 13$  sec,  $t = 104$  sec, and  $t = 194$  sec. Image width =  $1 \mu\text{m}$ .

See article by Winkel et al.

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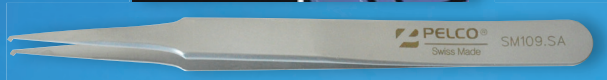
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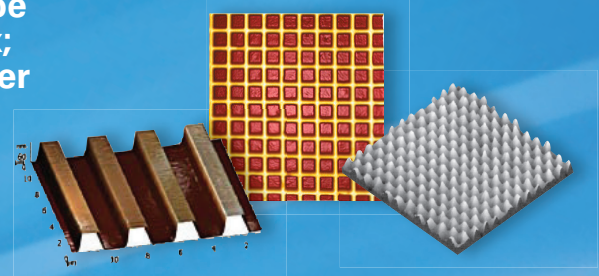
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